

<b>Notice of References Cited</b>	Application/Control No. 10/055,694	Applicant(s)/Patent Under Reexamination TERAGUCHI ET AL.	
	Examiner DEBBIE M LE	Art Unit 2167	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,789,088 B1	09-2004	Lee et al.	707/100
*	B	US-5,995,095 A	11-1999	Ratakonda, Krishna	715/500.1
	C	US-			
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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